

Application/Control	No. Applicant(s)/Patent Reexamination	under
09/395,207	AN ET AL.	
Examiner	Art Unit	
Michael Y. Won	2155	

SEARCHED				
Class	Subclass	Date	Examiner	
709	223	7/15/2002	MW	
719	315, 316	1/14/2004	MW	
719	317	1/14/2004	MW	
707	10, 100	6/15/2004	MW	
345	853	6/15/2004	MW	
379	230	6/15/2004	MW	
713	2	6/15/2004	MW	
717	108	6/15/2004	MW	
709	202	6/15/2004	MW	
719	315, 316	7/14/2005	MW	

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
315, 316	7/20/2005	MW		
108, 116	7/20/2005	MW		
203, 223	7/20/2005	MW		
	-			
	Subclass 315, 316 108, 116	Subclass Date 315, 316 7/20/2005 108, 116 7/20/2005		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	7/15/2002	MW		
APPEAL BRIEF CONFERENCE WITH PRIMARY	1/13/2004	MW		
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	1/14/2005	MW		
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	6/15/2005	MW		
DISCUSSED CASE WITH PRIMARY: MAJID BANANKHAH	7/14/2005	MW		
DISCUSSED CASE WITH PRIMARY: ST.JOHN COURTENAY III (DIRECTED EXAMINER TO SEARCH 719/315;316	7/14/2005	MW		
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	7/14/2005	MW		
NPL: IEEE	7/14/2005	MW		